JC20 Rec'd PET/PTO 18 OCT 2003

Sheet 1 of 1

Form PTO-1449 (REV. 8-83)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 125664			APPLICATION NO. New U.S. National Stage of PCT/JP04/006003			
INFORMATION DISCLOSURE STATEMENT						1		5537	1	
(Use several sheets if necessary)					APPLICANT Makoto IIDA					
				FILING DATE October 18, 2005						
U.S. PATENT DOCUMENTS										
EXAMINER								SUB		
INITIAL		DOCUMENT NUMBER	DATE		NAME			CLASS	CLASS	
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FOREIGN PATENT DOCUMENTS										
				D. A 1770	COLDIT	COUNTRY		CLASS	SUB CLASS	
		DOCUMENT NUMBER	-	DATE				CLASS	CLASS	
Smm	1	JP A 2002-201093 w/abstr. & trans.		16/2002	JAPAN					
Smm	2	JP A 2000-001391 w/abstr. & trans.	01/	07/2000	JAPAN					
Smm	3	JP A 09-263485 w/abstr. & trans.	10/	07/1997	JAPAN					
Smm	4	JP A 11-147786 w/abstr. & trans.	06/	02/1999	JAPAN			ļ		
Smm	5	JP A 2000-044388 w/abstr. & trans.	02/	15/2000	JAPAN		-		•	
Smm	6	JP A 11-349394 w/abstr. & trans.	12/	21/1999	JAPAN .					
Smm	7	JP A 2002-057160 w/abstr. & trans.	02/	22/2002	JAPAN					
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)										
Smm	8	V.V. VORONOKOV; "The Mechanism of Swirl Defects Formation in Silicon"; Journal of Crystal Growth; Vo								
_		March 1982; pp. 625-643								
		·								
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EXAMINER	<i>入</i>	M. Malik Fielch DATE CONSIDERED 03/14/2007								
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.										

Date: October 18, 2005